## **Semiconductor industry – Challenges and Opportunities**

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## **Outline**

- Hyperconnected Age – Role of semiconductors
- What is semiconductor
	- MOSFET and Scaling
	- Multigate Transistors
		- FinFET
		- Thin-Body Transistor
- Compact Modeling of FinFET and UTB FET
- What next?

## Hyperconnected Age

- We are living in an unprecedented era of hyperconnectivity that is redefining our societies, cultures, and communications. **THINGS** 50 billion
- And it has only just begun!



## Hyperconnected Age

#### • Present

- Facebook has more than 1.4 billion users worldwide, creating a hyperconnected, global social network
- Human to Device interaction

#### • Future

– Device to Human interaction





– Device to Device interaction

CISCO – By 2020, there will be 50 billion networked devices.

## Electronics industry

- Playing important role in making this planet smarter!
- Key enabling technologies
	- Internet of things KETs drive new developments across a broad range of industries
	- Cloud
	- Healthcare
	- Robotics
	- Automobile
	- Food



#### Internet of things



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#### IoT & Cloud – Data and Computation





## $We arab le Electronics$



Need ultra-low power devices and Sensors and Sensors and the Constant of the C

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moisture on your body to heat

#### Healthcare – Implantable Electronics







## 5G –Machine communication



#### The Deconstructed Cell Phone



#### Hint: It's All About the Microelectronics!

Semiconductors – Heart of technological progress and innovation

• The semiconductor is one of the most pervasive and powerful inventions in human history.

Top Innovations since the wheel:

**Printing Press Electricity Penicillin Semiconductor** 

Nobel Prize in Physics 2014 *"invention of efficient blue LEDs"* KETs drive new developments across a broad range of industries



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#### Economic impact of semiconductors

- Semiconductors touch every sphere of economic activity.
- Direct: ~\$300 bn
- Indirect
	- Material/equipment
- Induced
	- consumer market
- Downstream – Other industry



### What is semiconductor?



Source: Anandtech

#### Semiconductor Devices – Junction



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#### Semiconductor Devices – MOSFET



Saturation mode at point of pinch-off

Saturation mode

### Semiconductor devices to circuits

#### Flip-flop

#### NOT gate





Full Adder





### Semiconductor circuits to Products



#### Today's ICs Multiple metal layers **AUGE 1998** Second 3D ICs



**System in Package (SIP)** 





#### ★ SOC/Wafer Level Packaging

# How do you make these?





#### **Bunny Suits!**



**10B Transistors** per cm<sup>2</sup>







#### **Sillicon "Wafers"** \$5B Fabrication Facility Finish



## Building block – (tiny) MOSFET!

• MOSFET is a transistor used for amplifying or switching electronic signals.



## Invention of Transistor

- First Transistor (1947-1948) at AT&T's Bell Labs
	- Point Contact Transistor
	- First transistor was bipolar contact transistor
	- Material Germanium





## Invention of Transistor



William Shockley

- Worked on theory of Diode, Transistor, Thyristor etc.
	- Invented First transistor at Bell Labs
	- Received Nobel Prize in 1956
- Formed Shockley semiconductor in Mountain View, California in 1956
- Employees of Shockley semiconductor (Robert Noyce, Gordon Moore, ….)
	- These employees opened 65 companies in next 20 years including Intel, AMD, Fairchild,…

## Integrated Circuit (IC)

- IC Electronic circuit manufactured on the surface of a thin substrate of semiconductor material.
- Additional materials are deposited and patterned to form interconnections between semiconductor devices.





• ICs are used in virtually all electronic equipment today and have revolutionized the world of electronics.

# Invention of Integrated Circuits

- Jack Kilby (at *Texas Instruments*) demonstrated first working IC in 1958.
	- Jack Kilby was awarded the Nobel Prize in Physics 2000.
	- Kilby's work was named an IEEE Milestone in 2009.



First IC **First handheld Calculator** 



- Robert Noyce (at *Fairchild Semiconductor*) also invented IC separately six months later than Kilby.
	- It was made of silicon, whereas Kilby's chip was made of germanium.
	- Fairchild Semiconductor was also home of the first silicon gate IC technology with self-aligned gates, which stands as the basis of all modern CMOS computer chips.

### Bulk MOSFET



Figures: T.Liu, SRC/GRC e-Workshop, November 2012

### Bulk MOSFET

- Drain current in MOSFET (ON operation)  $I_{ON}=\mu$ W  $\frac{1}{L} C_{ox} (V_{DD} - V_{TH})^2$
- Drain current in MOSFET (OFF operation)  $I_{OFF} \propto 10$  $\frac{V_{GS}-V_{TH}}{2}$  $\boldsymbol{S}$
- **Desired**
- $C_{ox} = \varepsilon_{ox}/t_{ox} =$ oxide cap. S – Subthreshold slope
- $\mathbf{High} \mathbf{I_{ON}} \left( \downarrow\mathbf{L}, \uparrow\mathbf{Cox}, \uparrow\mathbf{V_{DD}}\mathbf{-V_{TH}} \right)$
- Low  $I_{\text{OFF}} (\uparrow V_{\text{TH}}, \uparrow S)$

#### **Moore's Law:**

The defining features of the integrated circuit technology (size, speed, cost) follow an exponential growth pattern over time Moral: Computing power while cost + exponentially!



#### Technology Scaling drives down the cost

- **Scaling:** At each new node, all geometrical features are reduced in size to 70% of the previous node.
- **Reward:** Reduction of *circuit size by half*.
	- Twice number of circuits on each wafer
	- Cost per circuit is reduced significantly.  $I_{ON}=\mu$

#### Moore's Law It's not technology!  $\rightarrow$  It's economy.



In 1978, a commercial flight between New York and Paris cost around \$900 and took seven hours. If the principles of Moore's Law had been applied to the airline industry the way they have to the semiconductor industry since 1978, that flight would now cost about a penny and take less than one second.

- Ways to Huge Profits
	- High performance and Low Cost

W

 $\frac{1}{L} C_{ox} (V_{DD} - V_{TH})^2$ 

– Achieved by making everything SMALLER



#### Strained Silicon  $I_{ON} = \mu$  $W$  $\frac{1}{L}C_{ox}(V_{DD}-V_{TH})^2$

Silicon is placed on substrate having large atomic spacing













#### **Methods of straining**

-Burried SiGe –Biaxial -Uniaxial Stress S/D SiGe

### Technology Trend



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Source : www.intel.com

## Thin Depletion Layer - Problem



- $Q_G = Q_i + Q_b$
- Charge sharing



## Short Channel – Big Problem



#### **MOSFET becomes "resistor" at small L.**

Chenming Hu, "Modern Semiconductor Devices for ICs" 2010, Pearson

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# Making Oxide Thin is Not Enough



#### **Gate cannot control the leakage current paths that are far from the gate.**

#### Good Old MOSFET has reached its Limits







- **Ioff is bad**
- **Size and dopant variations**

 **High Vdd, Power, Design Cost**

#### What can we do?



#### May 4, 2011 The New York Times Front Page

• **Intel will use 3D FinFET at 22nm**

• **Most radical change in decades**

• **There is a competing SOI technology**



or fins, that rise above the chip's surface

independently invented the first integrated circuits that became the basic building block of electronic devices in the information age.

# One Way to Eliminate Si Far from Gate

#### **Thin body controlled By multiple gates.**



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N. Lindert et al., DRC paper II.A.6, 2001

#### 40nm FinFET – 1999 **30nm Fin allows 2.7nm SiO2 & undoped body**

**ridding random dopant fluctuation.** 



X. Huang et al., IEDM, p. 67, 1999

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#### Introduced New Scaling Rule **Leakage is well suppressed if Fin thickness < Lg**









### State-of-the-Art **14nm** FinFET

#### **Transistor Fin Improvement**



 $\frac{10}{30}$   $\frac{201}{4}$  rce: Anandtech  $\frac{10}{30}$   $\frac{1}{30}$   $\frac{1}{30}$   $\frac{44}{50}$ 

42 nm

## **2nd Way to Eliminate Si far from Gate Ultra-thin-body SOI (UTB-SOI)**



## FDSOI Roadmap

• From a global cooperation ST‐IBM‐LETI have enabled an FD-SOI 3-node roadmap.



#### Main Differences



### Compact Modeling or SPICE Modeling



**Medium of information exchange**



- Good model should be
	- **Example:** Trustworthy simulations.
	- **Simple:** Parameter extraction is easy.
- Balance between accuracy and simplicity depends on end application
- Excellent Convergence
- Simulation Time ~µ*sec*
- Accuracy requirements
	- $-$  ~ 1% RMS error after fitting
- Example: BSIM6, BSIM-CMG

### BSIM-CMG and BSIM-IMG

- **Berkeley Short-channel IGFET Model**
- **First industry standard SPICE model for IC simulation**
- **Used by hundreds of companies for IC design since 1997**
- **BSIM FinFET model became industry standard in March 2012**

**It's Free**

#### **BSIM-IMG:** Length scaling@low Vds



UTBBSOI FET, Tsi=12nm Yogesh S. Chauhan, IIT Kanpur 50

## Common-Multi-Gate Modeling

- Common Multi-gate (BSIM-CMG):
	- All gates tied together



- Surface-potential-based core I-V and C-V model
- Supports double-gate, triple-gate, quadruple-gate, cylindrical-gate; Bulk and SOI substrates

#### Global fitting with 30nm–10µm FinFETs **BSIM-CMG**



#### What Next?



**Vertical or Horizontal** 

#### **Improved electrostatics**

- Precision etch and CMP
- Scaled metals
- **High Aspect Ratio ALD**

#### **Improved mobility**

- Epi structure
- III-V gate interface
- New material CMP

- Epi structure
- Multi-pass CMP
- Precision etch & CMP

## Modeling of III-V FinFET

#### **Quantum Capacitance Modeling**



Avirup Dasgupta et. al., "Analysis and Modeling of Quantum Capacitance in III-V Transistors", submitted in ICEE Bangalore, 2014.

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## Modeling of III-V FinFET



Schematic showing sidewall channels and 2-DEG channel in  $Fig. 1.$ AlGaN/GaN based FinFET devices; (a) Wide fin-width device, (b) Narrow fin-width device [12].



Fig. 3. Subthreshold behaviour of model with experimental data [12], for  $W_{fin}$ =80nm, 120nm, 140nm, 180nm and 200nm and  $Lg = 1.0 \mu m$ . Drain current is normalized with total gate width  $(W_{fin} + 2H_{fin})$ , where  $H_{fin} = 120nm$ .

#### • Chandan Yadav et. al., "Modeling of GaN-Based Normally-Off FinFET", IEEE ELECTRON DEVICE LETTERS, June 2014.

#### Forward Looking Modeling of 2D Semiconductor FET a



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# Joint Development & Collaboration

• Working closely with universities/companies on model development and support



# Upcoming Book on FinFET Model

#### FinFET Modeling for IC Simulation and Design: Using the BSIM-CMG Standard

# **Authorize School Engineering School Sch**

Using the BSIM-CMG Standard



**Yogesh Singh Chauhan<br>Darsen Lu** Sriramkumar Venugopalan **Sourabh Khandelwal Juan Pablo Duarte Navid Paydavosi Ali Niknejad Chenming Hu** 



- 1. FinFET- from Device Concept to Standard Compact Model
- 2. Analog/RF behavior of FinFET
- 3. Core Model for FinFETs
- 4. Channel Current and Real Device Effects
- 5. Leakage Currents
- 6. Charge, Capacitance and Non-Quasi-Static Effect
- 7. Parasitic Resistances and Capacitances
- 8. Noise
- 9. Junction Diode Current and Capacitance
- 10. Benchmark tests for Compact Models
- 11. BSIM-CMG Model Parameter Extraction

#### 12. Temperature Effects

## Summary

- Future is beyond imagination.
- Challenges
	- Technology Hardware and Software
	- Need Innovation
- Opportunities
	- Entrepreneurship
	- Research
	- Jobs (private/public)
- Knowledge economy

### Are you ready?

#### Present Future



